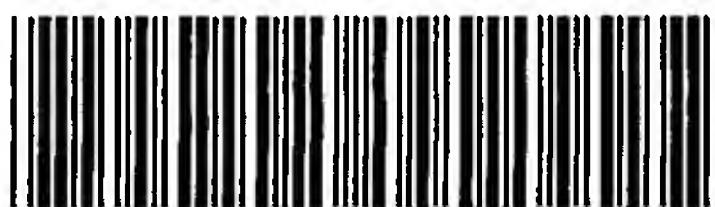


Search Notes**Application/Control No.**

10/532,424

Examiner

Steven D. Maki

Applicant(s)/Patent under Reexamination

FUJII ET AL.

Art Unit

1733

SEARCHED

Class	Subclass	Date	Examiner
152	154.2		
	209.17		
156	110.1		
73	146		
29	402.03		
	426.1		
updated	above	6/24/2007	<i>ADM</i>

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
none	6/24/2007	<i>ADM</i>

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner